

Course Structure

No	Information of Characterization of Materials (2019-2020)	
1	Unit name:	Characterization of Materials
2	Code:	Met- 51051
3	Classification:	Engineering subject
4	Credit value:	3
5	Semester/ Year Offered:	1/5
6	Pre-requisite:	
7	Mode of delivery:	Lecture, Tutorial, Assignment
8	Assessment system and breakdown of marks:	
	Test	30%
	Mid-term/ final Examination	70%
9	Academic staff teaching unit:	1
10	<p>Course outcome of unit:</p> <p>In this course, students will be able to</p> <ul style="list-style-type: none"> <li>- apply the varieties of microscopic and X-ray spectroscopic techniques.</li> <li>- identify the methodologies and applications various characterization techniques.</li> <li>- use the modern instruments for characterizing materials.</li> </ul>	
11	<p>Synopsis of unit:</p> <p>The course describes light microscopy, X-ray diffraction methods (XRD), transmission electron microscopy (TEM), scanning electron microscopy (SEM) and X-rays fluorescence for elementals analysis (XRF), atomic absorption spectroscopy (AAS), thermal analysis and non-destructive testing techniques. How to characterize and determine chemical compositions &amp; to observe internal structure.</p>	

12	<p>Topic:</p> <p>Chapter 1</p> <p><b>Light Microscopy</b></p> <p>Optical Principles</p> <p>Image Formation</p> <p>Resolution</p> <p>Effective Magnification</p> <p>Brightness and Contrast</p> <p>Depth of Field</p> <p>Aberrations</p> <p>Instrumentation, Illumination System, Objective Lens and Eyepiece</p> <p>Steps for Optimum Resolution</p> <p>Steps to Improve Depth of Field</p> <p>Specimen Preparation: Sectioning, Cutting, Microtomy, Mounting, Grinding and Polishing, Etching</p> <p>Imaging Modes</p> <p>Bright-Field and Dark-Field Imaging</p> <p>Phase-Contrast Microscopy</p> <p>Polarized-Light Microscopy</p> <p>Nomarski Microscopy</p> <p>Fluorescence Microscopy</p> <p>Confocal Microscopy</p> <p>Working Principles</p> <p>Three-Dimensional Images</p> <p>Chapter 2</p> <p><b>X-Ray Diffraction Methods</b></p> <p>X-Ray Radiation</p> <p>Generation of X-Rays</p> <p>X-Ray Absorption</p> <p>Theoretical Background of Diffraction</p> <p>Diffraction Geometry</p> <p>Bragg's Law</p> <p>Reciprocal Lattice</p> <p>Ewald Sphere</p> <p>Diffraction Intensity</p> <p>Structure Extinction</p> <p>X-Ray Diffractometry</p> <p>Instrumentation</p> <p>Samples and Data Acquisition</p> <p>Sample Preparation</p> <p>Acquisition and Treatment of Diffraction Data</p> <p>Preferential Orientation</p> <p>Crystallite Size</p> <p>Residual Stress</p> <p>Applications</p> <p>Crystal-Phase Identification</p>
----	---

<p>Quantitative Measurement</p> <p>Chapter 3</p> <p><b>Transmission Electron Microscopy</b></p> <p>Instrumentation</p> <p>Electron Sources</p> <p>Thermionic Emission Gun</p> <p>Field Emission Gun</p> <p>Electromagnetic Lenses</p> <p>Specimen Stage</p> <p>Specimen Preparation</p> <p>Pre-thinning</p> <p>Final Thinning</p> <p>Electrolytic Thinning</p> <p>Ion Milling</p> <p>Ultramicrotomy</p> <p>Image Modes</p> <p>Mass–Density Contrast</p> <p>Diffraction Contrast</p> <p>Phase Contrast</p> <p>Selected-Area Diffraction (SAD)</p> <p>Selected-Area Diffraction Characteristics</p> <p>Single-Crystal Diffraction</p> <p>Identification of Crystal Phases</p> <p>Multicrystal Diffraction</p> <p>Images of Crystal Defects</p> <p>Dislocations</p> <p>Chapter 4</p> <p><b>Scanning Electron Microscopy</b></p> <p>Instrumentation</p> <p>Optical Arrangement</p> <p>Signal Detection</p> <p>Detector</p> <p>Probe Size and Current</p> <p>Contrast Formation</p> <p>Electron–Specimen Interactions</p> <p>Topographic Contrast</p> <p>Compositional Contrast</p> <p>Working Distance and Aperture Size</p> <p>Acceleration Voltage and Probe Current</p> <p>Astigmatism</p> <p>Specimen Preparation</p> <p>Preparation for Topographic Examination</p> <p>Charging and Its Prevention</p> <p>Preparation for Microcomposition Examination</p> <p>Electron Backscatter Diffraction</p> <p>Applications of EBSD</p>
---

<p>Environmental SEM</p> <p>Chapter 5</p> <p><b>X-Ray Spectroscopy for Elemental Analysis</b></p> <p>Features of Characteristic X-Rays</p> <p>Types of Characteristic X-Rays</p> <p>Selection Rules</p> <p>Comparison of K, L, and M Series</p> <p>X-Ray Fluorescence Spectrometry</p> <p>Wavelength Dispersive Spectroscopy</p> <p>Analyzing Crystal</p> <p>Wavelength Dispersive Spectra</p> <p>Energy Dispersive Spectroscopy</p> <p>Detector</p> <p>Energy Dispersive Spectra</p> <p>Advances in Energy Dispersive Spectroscopy</p> <p>XRF Working Atmosphere and Sample Preparation</p> <p>Energy Dispersive Spectroscopy in Electron Microscopes</p> <p>Scanning Modes</p> <p>Qualitative and Quantitative Analysis</p> <p>Qualitative Analysis</p> <p>Quantitative Analysis</p> <p>Quantitative Analysis by X-Ray Fluorescence</p> <p>Chapter 6</p> <p><b>Thermal Analysis</b></p> <p>Common Characteristics</p> <p>Thermal Events</p> <p>Enthalpy Change</p> <p>Instrumentation</p> <p>Experimental Parameters</p> <p>Differential Thermal Analysis and Differential Scanning Calorimetry</p> <p>Working Principles</p> <p>Differential Thermal Analysis</p> <p>Differential Scanning Calorimetry</p> <p>Temperature-Modulated Differential Scanning Calorimetry</p> <p>Experimental Aspects</p> <p>Sample Requirements</p> <p>Baseline Determination</p> <p>Effects of Scanning Rate</p> <p>Measurement of Temperature and Enthalpy Change</p> <p>Transition Temperatures</p> <p>Measurement of Enthalpy Change</p> <p>Calibration of Temperature and Enthalpy Change</p> <p>Applications</p> <p>Determination of Heat Capacity</p> <p>Determination of Phase Transformation and Phase Diagrams</p> <p>Applications to Polymers</p>
--

Course Structure

	<p>Thermogravimetry  Instrumentation  Experimental Aspects  Samples  Atmosphere  Temperature Calibration  Heating Rate  Interpretation of Thermogravimetric Curves  Types of Curves  Temperature Determination  Applications</p> <p>Chapter 7  <b>Atomic Absorption Spectrometry (AAS)</b>  Introduction  Basic principle  Flame AAS  Atomic Absorption Spectrometry with graphite furnace (GFAA)</p> <p>Chapter 8  <b>Non-destructive testing Methods</b></p>
14	<p>Main Reference</p> <ul style="list-style-type: none"> <li>- Materials Characterization- An introduction to Microscopic and Spectroscopic Methods, Yang Leng, 2<sup>nd</sup> edition</li> </ul>
15	<p>Additional references:</p> <ul style="list-style-type: none"> <li>- Elements of Physical Metallurgy, Albert G. Guy and John J. HREN, 3<sup>rd</sup> Edition</li> <li>- Solid State Chemistry and Its Applications</li> </ul>